

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHOI ET AL.	
		Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

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	C	US-5,198,746	03-1993	Gyugyi et al.	323/207
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NON-PATENT DOCUMENTS

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	V	Stamp et al., Fault Location Technique for Six Phase Transmission Lines With Unsynchronised Phasors, IEEE 1999, Pages 663-667
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.